

<b>Notice of References Cited</b>	Application/Control No. 09/734,917	Applicant(s)/Patent Under Reexamination GOODMAN, BRIAN GERARD	
	Examiner Satish S. Rampuria	Art Unit 2124	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,023,727 A	02-2000	Barrett et al.	709/221
	B	US-6,401,198 B1	06-2002	Harmer et al.	713/1
	C	US-6,457,175 B1	09-2002	Lerche, Robert A.	717/173
	D	US-6,601,212 B1	07-2003	Guha et al.	714/776
	E	US-5,623,604 A	04-1997	Russell et al.	717/167
	F	US-6,625,754 B1	09-2003	Aguilar et al.	714/15
	G	US-6,266,809 B1	07-2001	Craig et al.	717/173
	H	US-5,815,722 A	09-1998	Kalwitz et al.	717/178
	I	US-6,144,992 A	11-2000	Turpin et al.	709/208
	J	US-6,205,580 B1	03-2001	Hirose, Takahiro	717/162
	K	US-6,308,325 B1	10-2001	Dobbek, Jeffrey J.	717/178
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Electronic Engineering, Reducing development times for embedded systems, Sep 1, 1999, pg. 35
	V	Corcoran, Cate, PC makers look beyond RISC to faster VLIW systems, Jan 17, 1994, InfoWorld, Vol. 16, issue 3, pg 29
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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